1980 editorial index

AUTOMATIC TEST AND INSPECTION

Microprocessor design and production testing — Jan p. 26
The British approach to automatic testing — Mar p. 45
Instrument control improves analyses — Apr p. 62
Testing Ford's V-8 — Oct p. 21

INSPECTION

NDT with a big X — Jan p. 38
One variable measurement in the hand . . . — Mar p. 54
To pull or not to pull — Apr p. 50
X-ray with muscle — Apr p. 59
Analyzing pump performance — May p. 40
Coating inspection — May p. 78
SEM in materials science — Jun p. 28
Screw thread management — Aug p. 19
Radiography is given a whirl — Sep p. 34
Magnetic particle technology — Sep p. 40
Testing seamless pipe — Sep p. 54
Strobe light improves inspection — Oct p. 44
An angle on accuracy — Nov p. 34
Fixed gages — Nov p. 54

MANAGEMENT

The software development notebook—a proven technique — Jan p. 18
A new look at total quality control — Jan p. 34
QC—a line function — Feb p. 16
Dr. W. Edwards Deming—the statistical control of quality, Part I — Feb p. 38
Dr. W. Edwards Deming—the statistical control of quality, Part II — Mar p. 34
Dr. Milton Friedman—on the economics of quality — Apr p. 24
Quality starts at the beginning — Apr p. 54
The cause and effect at Three Mile Island, Part I — May p. 22
A data acquisition overview — May p. 47
Quality and management style — Jun p. 36
The cause and effect at Three Mile Island, Part II — Jun p. 42
Quality—a management gambit — Aug p. Q1
- Introduction — Aug p. Q1
- The policy — Aug p. Q3
- The manual—what — Aug p. Q4
- The manual—why — Aug p. Q5
- The organization — Aug p. Q11
- The program — Aug p. Q12
- Quality improvement activities — Aug p. Q13
- Measuring maturity — Aug p. Q15
- No miracle—just good management — Aug p. Q19
- Who needs training? — Aug p. Q24
- "It does work" — Aug p. Q26

Portec's comprehensive quality program — Sep p. 61
Training for tomorrow — Sep p. 24
Large transportation vehicles—the considerations of quality — Oct p. 36
Robots in light industry — Nov p. 42
Electronic scales and the science of weighing — Dec p. 39

PROCUREMENT

Vendor evaluation checklist set #5 — Jan p. 46
Selecting a testing laboratory — Jun p. 24
Power cycling — Sep p. 29
Total quality—design and conformance — Oct p. 24
ECL testing—speed makes it different — Nov p. 27

PROCESS QUALITY CONTROL

Process improvement with quality control, Part I — Apr p. 31
Process improvement with quality control, Part II — May p. 66

Q.C. IN MANUFACTURING

Craftsman in a box — Jan p. 75
Color makes clamps champs — Feb p. 24
Old machines produce new parts — Feb p. 34
Broadcasting—yesterday and today — Mar p. 24
Compressing compressor test time — Jun p. 34
The pipeline crawler — Nov p. 18
Force is basic — Dec p. 21
Analyzing the plating bath — Dec p. 34

QUALITY ENGINEERING

A practical system for equipment calibration — Mar p. 41
Statistics—a new dimension in component reliability, Part I — Apr p. 38
What is a professional? — Apr p. 45
Statistics—a new dimension in component reliability, Part II — May p. 56
Comparative technology — May p. 84
Corrective action chronicle — Jun p. 18
Indentation hardness testing — Sep p. 19
Electrotopography—is it the next NDT breakthrough? — Sep p. 84
Understanding confidence limits, Part I — Oct p. 29
Understanding confidence limits, Part II — Nov p. 22

RELIABILITY ENGINEERING

DSC to UV-VIS—an overview of materials analysis equipment, Part I — Jan p. 64
DSC to UV-VIS—an overview of materials analysis equipment, Part II — Feb p. 26
Measure your own work — Feb p. 36
Finding the failure rate — Apr p. 18
A clue from Columbo — Dec p. 54

SPECIAL FEATURE

1979 Editorial index — Jan p. 82
1980 Inspection, Testing and Quality Assurance Show — May p. 32

Viewing heart to heart—live May p. 74
ATE East preview Jun p. 38
1980 International Machine Tool Show preview Aug p. 33
ASNT '80 preview Sep p. 48
Annual salary survey Oct p. 46
Quality cost survey Jul p. 16

BASIC TRAINING REVIEW

Sampling—common sense and a return to basics Jan p. 55
Simplified theory of laser operation Feb p. 45
Welding quality control Apr p. 61
Universal bevel protractor May p. 91
Life testing and the Poisson Table, Part VII Jun p. 51
The inspection record Aug p. 33
Life testing and the Poisson Table, Part VIII Sep p. 67
Height gage tips Oct p. 54
Quality of writing Nov p. 69
A QC in formation system Dec p. 57

EDITORIAL COMMENT

New law—precedence for others to follow Jan p. 5
Recession? . . . no participation this time Feb p. 5
A repeat performance Mar p. 5
Attacks on big business continue Apr p. 5
Expo TIME May p. 5
Failure . . . a growing black cloud Jun p. 5
From adversaries to partners—we hope Jul p. 5
Turning it around—everybody's job Aug p. 7
A universal quality policy Sep p. 5
In his own image Oct p. 5
QC . . . a tool for all disciplines Nov p. 5
At least we gave Jimmy four years Dec p. 5

INSTRUMENT[illegible]TION SCOUTING REPORT

Gaging columns gain digital display Jan p. 61
Putting the CAP on equipment calibration Jan p. 62
Thinline PAUs are PCB testing pals Feb p. 30
QADM means improved CMM performance Feb p. 30
Thermal system localizes temperature at test socket Mar p. 65
Computerized "talking" alarm system Mar p. 65
Plating thickness for continuous strip applications Apr p. 70
Speech synthesizer provides verbal instruction capabilities Apr p. 70
Microprocessor-controlled dual beam spectrophotometer May p. 88
Interferometer for precision measurements May p. 88
Laminar flow enclosures for cleanroom enviroments Jun p. 46
Microprocessor-based controller/programmer Jun p. 46
ATE system for discrete devices Aug p. 27
Volumeter for packing density evaluations Sep p. 71
Touch-display instrument controller provides simplified operator response Sep p. 71
Test package for in-circuit analog and digital LSI Oct p. 53
IEEE-488 bus-compatible electrometer/multimeter Oct p. 53
Analyzer for color measurement applications Nov p. 66
Non-contact laser measurement system Dec p. 62
ATE system for bare board testing Dec p. 62

AUTHORS

Berger, Dean M. May p. 78
Borucki, James E. Sep p. 40
Byerly, Bob Feb p. 24
Chamerda, Robert S. Aug p. 19
Chrones, Chris Apr p. 38
May p. 56
Cooper, James Oct p. 24
Crockett, David C. Apr p. 61
Crosby, Philip B. Jun p. 36
Aug p. Q15
Davidson, Dennis Dec p. 57
Deming, Dr. W. Edwards Aug p. Q26
Denton, Don Apr p. 18
Fagan, Virgil E. Jun p. 18
Gabriel, B.L. Jun p. 28
Galey, F.D. Mar p. 24
Grimm, Bill Feb p. 45
Gruenthal, Martin H. Jan p. 26
Hansen, Norman E. Feb p. 16
Harrington, H.J. Mar p. 41
Haskell, Robert A. Oct p. 29
Nov p. 22
Heldt, John J. Jun p. 51
Sep p. 67
Nov p. 69
Hershfield, Walton N. May p. 84
Hopkins, Robert Nov p. 27
Inskeep, G.W. Jr. May p. 22
Jun p. 42
Ishikawa, Kaoru May p. 97
Karatsu, Hajime Feb p. 53
Krashes, David Dec p. 60
LaPorte, Robert K. May p. 40
Lewis, Gary W. Aug p. Q24
McAteer, Owen J. Dec p. 54
McKissick, John M. Jr. Jan p. 18
Miller, Larry W. Apr p. 45
Mizuno, Shigeru Jun p. 53
Nelson, James A. Dec p. 28
Nygaard, George M. May p. 119
Ott, Ellis R. Apr p. 31
May p. 66
Painchaud, Phillip Feb p. 71
Price, Robert A. Jan p. 18
Rishel, Lew Apr p. 50
Sasaki, Naoto Jul p. 25
Shearsmith, J.A.G. Mar p. 45
Sherlock, Alan Dec p. 21
Stalker, Allan H. Aug p. 33
Stiles, Nelson C. Apr p. 54
Strange, Michael R. Sep p. 29
Trevedi, Sunil J. Apr p. 61
Turnbull, Don Aug p. Q5
Tustin, Wayne Jun p. 24
Vavken, Roland Mar p. 98
Von Osinski, Ralph Jan p. 34
Walker, Marvin H. Jr. Jan p. 55
Wollschlaeger, Les Aug p. Q13

MANAGEMENT VIEWPOINT

What to do before the auditor comes	Feb p. 51
Treating turnover trauma	Mar p. 73
Sexism has no place at work	May p. 95
Executive stress and you	Jul p. 22
How small businesses can attract big talent	Aug p. 45
Business language made plain	Oct p. 61
The mid-career crisis—and how to avoid it	Dec p. 73

MEASUREMENT/METRIC MEMO

No news	Jan p. 81
Making the best better	Apr p. 69
Productivity—try this one	Jun p. 57
Defect prevention	Sep p. 83
Nine out of ten doctors	Nov p. 80

QUALITY AND THE LAW

Whose state of the art?	Jan p. 77
Calling on the new troops—computers	Feb p. 47
Pondering the "Ransome" note	Mar p. 69
Fingers do the talking	Apr. p. 65
The ghost of Winamac	May p. 93
Market share liability	Jul p. 19
How long is safe?	Aug p. 43
Let's bail out quality	Sep p. 81
Unscrambling warranties	Oct p. 57
Think alternatives	Nov p. 77
The trouble with warnings	Dec p. 71

QUALITY AT RANDOM

Productivity and tools	Jan p. 101
StarLifter completes structures proof testing	Feb p. 67
Camera dives to the edge of creation	Mar p. 97
"Seek and find" hazardous wastes	Apr p. 95
Economical aspects of automated inspection	May p. 119
Quality—how sweet it is	Jun p. 79
Radiometric technique detects bearing wear	Oct p. 87
Quality control at Humko Sheffield	Nov p. 81
Seeking the quality minded laboratory	Dec p. 60

QUALITY IN JAPAN

Quality technique	Feb p. 53
QC circle activities	May p. 97
The Deming prize	Jun p. 53
Towards the creation of the new QC circle	Jul p. 25

THE QUALITY SCENE

On listening	Jan p. 79
Quality is free	Feb p. 49
"Me too"—the cost reduction chorus	Mar p. 71
Anatomy of Japanese success	Apr p. 67
Quality is management	Jun p. 55
A plethora of caues	Jul p. 21
The Kemeny report	Aug p. 47
Waiting around in Indiana	Sep p. 79
Is it plausible?	Oct p. 59
Massage and penetration	Nov p. 79
Beware of quality evaluation formulae	Dec p. 75

For a copy of this article, circle 9 on reader service card. Requests will be honored until supply is exhausted.

Call DuPont for Leak Detectors that remain reliable in tough service.

Rugged & reliable. Designed to withstand the jolts, jars and varied environments of everyday use. Have distinguished themselves for more than 30 years...in hundreds of installations.

Sensitive & fast. Detect leaks as small as 5×10^{-11} bar cm^3/sec with high speed, suitable for both production line and lab.

Options to match your needs. DuPont's 120SSA mass spectrometer Leak Detectors offer manual or semi-automatic operation, vacuum or pressure procedures, remote control, direct reading, and a variety of test ports and other accessories.

Get details and a quotation.
Call (302) 772-5481. Or write to: DuPont Company, Analytical Instruments Division, Room 38797, Wilmington, DE 19898.

Leak Detectors
Analytical Instruments Division

DUPONT

Circle 190 on reader information card